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Application/Control No.	Applicant(s)/Patent under Reexamination
10/792 218	SATOH ET AL.

Reexamination		
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Amy R. Cohen

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Class	Subclass	Date	Examiner
33	316	1/3/2005	ARC
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Updated		8/16/2005	ARC

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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